

Title (en)  
ASSEMBLY AND METHOD FOR TESTING INTEGRATED CIRCUIT DEVICES

Title (de)  
ANORDNUNG UND VERFAHREN ZUR PRÜFUNG VON INTEGRIERTEN SCHALTUNGSEINRICHTUNGEN

Title (fr)  
INSTALLATION ET PROCEDE DE TESTS DE CIRCUITS INTEGRES

Publication  
**EP 0882239 B1 20090603 (EN)**

Application  
**EP 97902776 A 19970117**

Priority  
• SE 9700068 W 19970117  
• US 59597996 A 19960206

Abstract (en)  
[origin: US5996102A] A testing assembly, and an associated method, for testing an integrated circuit device. The testing assembly is capable of testing an integrated circuit device having a large number of input and output terminals formed of either single-ended terminals or differential terminals. Static testing, both functional and parametric, can be performed upon the integrated circuit device. Additionally, dynamic testing of the integrated circuit device, even integrated circuit devices operable at high frequencies, is possible through operation of the testing assembly. Test signals are applied by way of signal rails to the device undergoing testing. A test signal response indicator is coupled to observe responses to the test signals.

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